

**A new measure for calculating multiple fault coverage of microprocessor self-test**

**Oyeniran, Adeboye Stephen; Odozi, Uzochukwu Eddie; Ubar, Raimund-Johannes** BEC 2016 : 2016 15th Biennial Baltic Electronics Conference : proceedings of the 15th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 3-5, 2016, Tallinn, Estonia 2016 / p. 75-78 : ill [http://www.estet.ee/record=b2150914\\*est](http://www.estet.ee/record=b2150914*est)

**New fault models and self-test generation for microprocessors using High-Level Decision Diagrams**

Jasnetski, Artjom; **Raik, Jaan; Tšertov, Anton; Ubar, Raimund-Johannes** 2015 IEEE 18th International Symposium on Design and Diagnostics of Electronic Circuits & Systems DDECS 2015 : 22-24 April 2015, Belgrade, Serbia : proceedings 2015 / p. 251-254 : ill

**Software-based self-test generation for microprocessors with high-level decision diagrams**

**Jasnetski, Artjom; Ubar, Raimund-Johannes; Tšertov, Anton; Brik, Marina** Proceedings of the Estonian Academy of Sciences 2014 / p. 48-61 : ill [https://artiklid.elnet.ee/record=b2665215\\*est](https://artiklid.elnet.ee/record=b2665215*est) <https://doi.org/10.3176/proc.2014.1.08> Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

**Software-based self-test generation for microprocessors with high-level decision diagrams**

**Ubar, Raimund-Johannes; Tšertov, Anton; Jasnetski, Artjom; Brik, Marina** LATW2014 : 15th IEEE Latin-American Test Workshop : Fortaleza, Brazil, March 12th-15th, 2014 2014 / [6] p. : ill